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STATEMENT BY APPLICANT**
(Not for submission under 37 CFR 1.99)

Application Number		10030019
Filing Date		2003-07-30
First Named Inventor	Mark D. Chuey	
Art Unit	2635	
Examiner Name	Nam V. Nguyen	
Attorney Docket Number	LEAR 04116 PUS	








	9	6822603		2004-11-24	Crimmins, et al.	
	10	5473317		1995-12-05	Inomata et al.	

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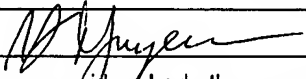
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	1	20020075133	A1	2002-06-20	Flick, Kenneth E.	
	2	20030033540	A1	2003-02-13	Fitzgibbon, James J.	
	3	20030118187	A1	2003-06-26	Fitzgibbon, James J.	
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	5	20040066936	A1	2004-04-08	Farris, Bradford L., et al.	
	6	20040110472	A1	2004-06-10	Witkowski, Todd R., et al.	
	7	20040243813	A1	2004-12-02	Farris, Bradford L., et al.	

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Examiner Name	Nam V. Nguyen	
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	3	5831548		1998-11-03	Fitzgibbon	
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